# N-Channel Power MOSFET 500 V, 1.5 $\Omega$

#### **Features**

- Low ON Resistance
- Low Gate Charge
- ESD Diode-Protected Gate
- 100% Avalanche Tested
- 100% Rg Tested
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### ABSOLUTE MAXIMUM RATINGS ( $T_C = 25$ °C unless otherwise noted)

Rating	Symbol	NDF	NDD	Unit
Drain-to-Source Voltage	$V_{DSS}$	500		V
Continuous Drain Current $R_{\theta JC}$	I <sub>D</sub>	5.5 (Note 1) 4.7		Α
Continuous Drain Current $R_{\theta JC}$ , $T_A = 100^{\circ}C$	I <sub>D</sub>	3.5 (Note 1)	3	Α
Pulsed Drain Current, V <sub>GS</sub> @ 10 V	I <sub>DM</sub>	20	19	Α
Power Dissipation $R_{\theta JC}$	$P_{D}$	30	83	W
Gate-to-Source Voltage	V <sub>GS</sub>	±30		V
Single Pulse Avalanche Energy, I <sub>D</sub> = 5.0 A	E <sub>AS</sub>	130	1	mJ
ESD (HBM) (JESD22-A114)	V <sub>esd</sub>	3000		V
RMS Isolation Voltage (t = 0.3 sec., R.H. $\leq$ 30%, T <sub>A</sub> = 25°C) (Figure 17)	V <sub>ISO</sub>	4500		٧
Peak Diode Recovery (Note 2)	dV/dt	4.5		V/ns
MOSFET dV/dt	dV/dt	60		V/ns
Continuous Source Current (Body Diode)	Is	5		Α
Maximum Temperature for Soldering Leads	TL	260		°C
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to	150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Limited by maximum junction temperature
- 2.  $I_S = 4.4 \text{ Å}, \text{ di/dt} \le 100 \text{ A/}\mu\text{s}, \text{ V}_{DD} \le \text{BV}_{DSS}, \text{ T}_J = +150 ^{\circ}\text{C}$

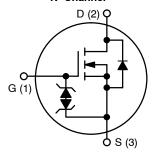


#### ON Semiconductor®

#### www.onsemi.com

V <sub>DSS</sub>	R <sub>DS(on)</sub> (MAX) @ 2.2 A		
500 V	1.5 Ω		

#### N-Channel





NDF05N50ZG, NDF05N50ZH TO-220FP CASE 221AH



NDD05N50Z-1G IPAK CASE 369D



NDD05N50ZT4G DPAK CASE 369AA

#### **ORDERING AND MARKING INFORMATION**

See detailed ordering, marking and shipping information on page 7 of this data sheet.

#### THERMAL RESISTANCE

Parameter		Symbol	Value	Unit
Junction-to-Case (Drain)	NDF05N50Z NDD05N50Z	$R_{\theta JC}$	4.2 1.5	°C/W
Junction-to-Ambient Steady State	(Note 3) NDF05N50Z (Note 4) NDD05N50Z (Note 3) NDD05N50Z-1	$R_{ hetaJA}$	50 38 80	

<sup>3.</sup> Insertion mounted

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Characteristic	Symbol	Test Conditions		Min	Тур	Max	Unit
OFF CHARACTERISTICS	-		-		•	•	•
Drain-to-Source Breakdown Voltage	BV <sub>DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	1	500			V
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS}/ \ \Delta T_{J}$	Reference to 25°C, I <sub>D</sub> = 1 mA			0.6		V/°C
Drain-to-Source Leakage Current	I <sub>DSS</sub>	.,	25°C			1	μΑ
		$V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V}$	150°C			50	
Gate-to-Source Forward Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ±20 V	•			±10	μΑ
ON CHARACTERISTICS (Note 5)							
Static Drain-to-Source On-Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V}, I_D = 2.2 \text{ A}$	4		1.25	1.5	Ω
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 50 \mu$	A	3.0	3.9	4.5	V
Forward Transconductance	9FS	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 2.5 A	4		3.5		S
DYNAMIC CHARACTERISTICS							
Input Capacitance (Note 6)	C <sub>iss</sub>			421	530	632	pF
Output Capacitance (Note 6)	C <sub>oss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		50	68	80	
Reverse Transfer Capacitance (Note 6)	C <sub>rss</sub>			8	15	25	
Total Gate Charge (Note 6)	$Q_g$			9	18.5	28	nC
Gate-to-Source Charge (Note 6)	$Q_{gs}$	\/ 050\/ L 5.4	•	2	4	6	
Gate-to-Drain ("Miller") Charge (Note 6)	$Q_{gd}$	$V_{DD} = 250 \text{ V}, I_D = 5 \text{ A}$ $V_{GS} = 10 \text{ V}$	,	5	10	15	
Plateau Voltage	V <sub>GP</sub>				6.5		V
Gate Resistance	R <sub>g</sub>			1.5	4.5	8	Ω
RESISTIVE SWITCHING CHARACTER	ISTICS		-		•	•	•
Turn-On Delay Time	t <sub>d(on)</sub>				11		ns
Rise Time	t <sub>r</sub>	V <sub>DD</sub> = 250 V, I <sub>D</sub> = 5 A	.,		15		]
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS} = 10 \text{ V}, R_G = 5 \Omega$			24		1
Fall Time	t <sub>f</sub>				14		1
SOURCE-DRAIN DIODE CHARACTE	RISTICS (T <sub>C</sub> =	25°C unless otherwise noted)					
Diode Forward Voltage	$V_{SD}$	I <sub>S</sub> = 5 A, V <sub>GS</sub> = 0 V				1.6	V
Reverse Recovery Time	t <sub>rr</sub>	$V_{GS} = 0 \text{ V}, V_{DD} = 30 \text{ V}$ $I_{S} = 5 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$			255		ns
Reverse Recovery Charge	Q <sub>rr</sub>				1.25		μС

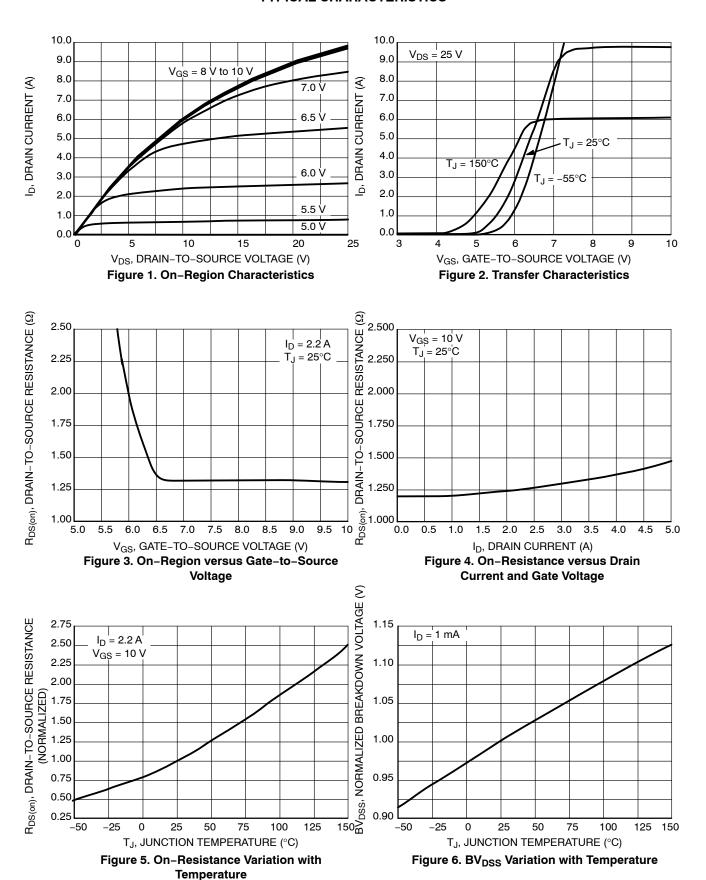
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Width ≤ 380 μs, Duty Cycle ≤ 2%.

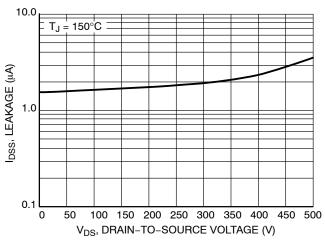
6. Guaranteed by design.

<sup>4.</sup> Surface mounted on FR4 board using 1" sq. pad size, (Cu area = 1.127 in sq [2 oz] including traces).

#### **TYPICAL CHARACTERISTICS**



#### **TYPICAL CHARACTERISTICS**



1200  $T_J^l = 25^{\circ}C$ 1100  $V_{GS} = 0 V$ 1000 f = 1 MHzC, CAPACITANCE (pF) 900 800 700 600 Ciss 500 400 300 200 Coss 100 0 0 45 50  $V_{DS}$ , DRAIN-TO-SOURCE VOLTAGE (V)

Figure 7. Drain-to-Source Leakage Current versus Voltage

Figure 8. Capacitance Variation

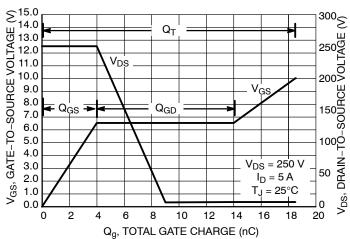
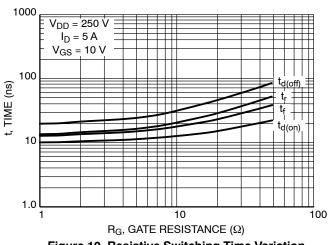


Figure 9. Gate-to-Source Voltage and
Drain-to-Source Voltage versus Total Charge

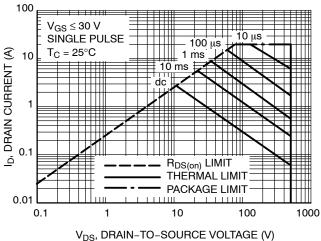


100 SOURCE CURRENT (A) 10  $T_J = 150^{\circ}C$ 1.0 <u>ŵ</u> -55°C 0.1 0.9 1.0 0.3 8.0 0.4 0.6 0.7 V<sub>SD</sub>, SOURCE-TO-DRAIN VOLTAGE (V)

Figure 10. Resistive Switching Time Variation versus Gate Resistance

Figure 11. Diode Forward Voltage versus Current

#### **TYPICAL CHARACTERISTICS**



100  $V_{GS} \leq 30 \text{ V}$ SINGLE PULSE 1 ms ID, DRAIN CURRENT (A)  $T_C = 25^{\circ}C$ 10 10 ms 0.1 R<sub>DS(on)</sub> LIMIT THERMAL LIMIT PACKAGE LIMIT 0.01 1000 0.1 10 100

Figure 12. Maximum Rated Forward Biased
Safe Operating Area NDF05N50Z

V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V)
Figure 13. Maximum Rated Forward Biased
Safe Operating Area NDD05N50Z

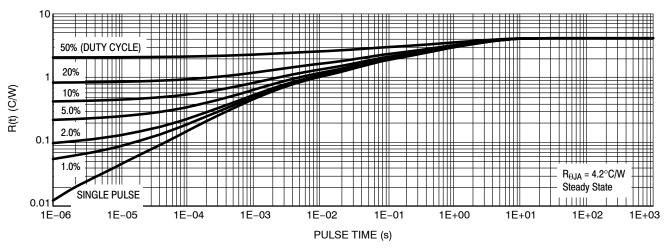


Figure 14. Thermal Impedance (Junction-to-Case) for NDF05N50Z

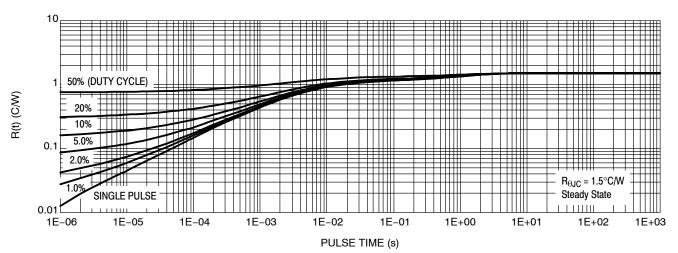


Figure 15. Thermal Impedance (Junction-to-Case) for NDD05N50Z

#### **TYPICAL CHARACTERISTICS**

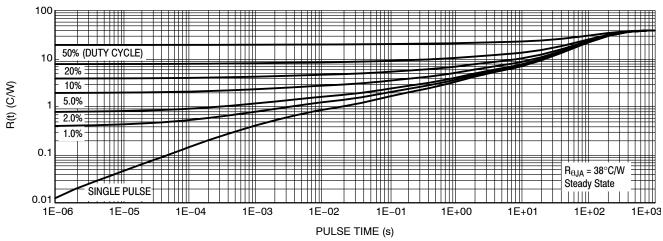


Figure 16. Thermal Impedance (Junction-to-Ambient) for NDD05N50Z

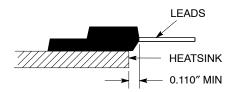


Figure 17. Isolation Test Diagram

Measurement made between leads and heatsink with all leads shorted together.

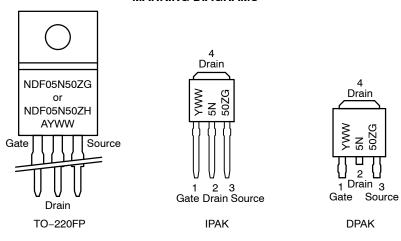
<sup>\*</sup>For additional mounting information, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### **ORDERING INFORMATION**

Order Number	Package	Shipping <sup>†</sup>
NDF05N50ZG	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDF05N50ZH	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDD05N50Z-1G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail
NDD05N50ZT4G	DPAK (Pb-Free, Halogen-Free)	2500 / Tape and Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### **MARKING DIAGRAMS**



A = Location Code

Y = Year

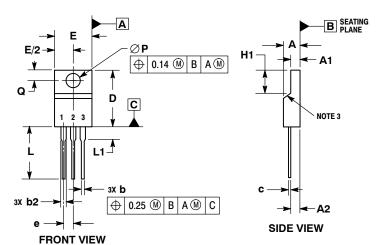
WW = Work Week

G, H = Pb-Free, Halogen-Free Package

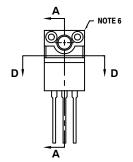
#### **PACKAGE DIMENSIONS**

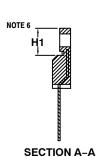
#### TO-220 FULLPACK, 3-LEAD

CASE 221AH **ISSUE F** 









**ALTERNATE CONSTRUCTION** 

- NOTES:

  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

  2. CONTROLLING DIMENSION: MILLIMETERS.

  3. CONTOUR UNCONTROLLED IN THIS AREA.

  4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH AND GATE PROTRUSIONS. MOLD FLASH AND GATE PROTRUSIONS NOT TO EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE TO BE MEASURED AT OUTERMOST EXTREME OF THE PLASTIC BODY.

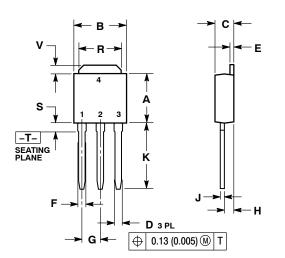
  5. DIMENSION DE DOES NOT INCLUDE DAMBAR PROTRUSION. LEAD WIDTH INCLUDING PROTRUSION SHALL NOT EXCEED 2.00.

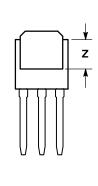
  6. CONTOURS AND FEATURES OF THE MOLDED PACKAGE BODY MAY VARY WITHIN THE ENVELOP DEFINED BY DIMENSIONS A1 AND H1 FOR MANUFACTURING PURPOSES.

	MILLIMETERS			
DIM	MIN	MAX		
Α	4.30	4.70		
A1	2.50	2.90		
A2	2.50	2.90		
b	0.54	0.84		
b2	1.10	1.40		
C	0.49	0.79		
D	14.70	15.30		
Е	9.70	10.30		
е	2.54	BSC		
H1	6.60	7.10		
L	12.50	14.73		
L1		2.80		
Р	3.00	3.40		
Q	2.80	3.20		

#### **PACKAGE DIMENSIONS**

## **IPAK** CASE 369D ISSUE C





- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: INCH.

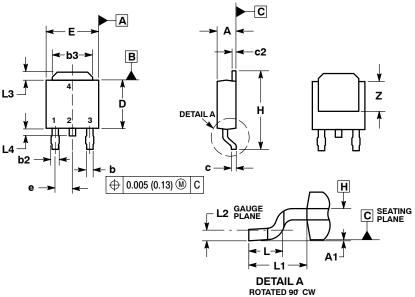
	INCHES		MILLIM	IETERS
DIM	MIN	MAX	MIN MAX	
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
C	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090 BSC		2.29 BSC	
H	0.034	0.040	0.87	1.01
۲	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
٧	0.035	0.050	0.89	1.27
7	0.155		2 02	

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN

#### PACKAGE DIMENSIONS

#### **DPAK (SINGLE GAUGE)**

CASE 369AA **ISSUE B** 



#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME
- Y14.5M, 1994.
  2. CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL
- NOT EXCEED 0.006 INCHES PER SIDE.
  DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
  DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

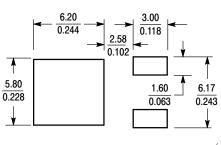
	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.030	0.045	0.76	1.14
b3	0.180	0.215	4.57	5.46
O	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
Е	0.250	0.265	6.35	6.73
е	0.090	BSC	2.29 BSC	
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.108 REF		2.74 REF	
L2	0.020	BSC	0.51 BSC	
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	

STYLE 2: PIN 1. GATE

2. DRAIN 3. SOURCE

DRAIN

#### **SOLDERING FOOTPRINT\***



(mm inches SCALE 3:1

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<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.